Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/841,367	TAY ET AL.	
Examiner	Art Unit	
Douglas Q. Tran	2624	

	SEARCHED				
Class	Subclass	Date	Examiner		
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	1.15				
	5.01 3.07 3.12				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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